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PTO/SB/08A	ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. 10/678549 (Cont. of 10/274,968)
LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	APPLICANT Randy J. Schwindt et al.	
(Use several sheets if necessary)	FILING DATE Herewith 10/02/03	GROUP 2829

FOREIGN PATENT DOCUMENTS

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
E.P.K.	AY	201205	12/1986	Europe	—	—		
E.P.K.	AZ	I-209380	8/23/1989	Japan	—	—		
E.P.K.	BA	2-220453	9/1990	Japan	—	—		

PTO/SB/08A		ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. 18/678549
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

E.P.K.	BB	Micromanipulator Company, Inc., "Test Station Accessories." (1983) <i>(marked unavailable)</i>
E.P.K.	BC	Micromanipulator Company, Inc., "Model 8000 Test Station." (1986) <i>(marked unavailable)</i>
E.P.K.	BD	"Model TPO3000 Series Thermochuck® Systems," four-page product note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
E.P.K.	BE	
E.P.K.	BF	"Application Note 1 Controlled Environment Enclosure," two-page application note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
E.P.K.	BG	Micromanipulator Company, Inc. "Model 8000 Test Station." (1988) <i>(marked unavailable)</i>
E.P.K.	BH	Applebay, Harry F. Deposition transcript (pp. 61-67) with exhibits 581 A.B.C. describing Flexion AP-1 probe station sold in 1987 (May 1988)
E.P.K.	BI	"Cross Section Signatone S-1240," one-page sketch prepared by Signatone counsel. <i>Feb. 1988</i>
E.P.K.	BJ	"S-1240," two-page product note, Signatone, San Jose, CA (February 1988 or earlier per Signatone counsel)
E.P.K.	BK	Y. Yamamoto, "A Compact Self-Shielding Prober . . ." IEEE Trans., Inst. and Meas., Vol. 38, pp. 1088-1093 (1989) <i>Dec.</i>
E.P.K.	BL	Temptronic's "Guarded" Chuck, one-page note describing guarding system of Temptronic Corporation of Newton, MA, dated 11/15/89.
E.P.K.	BM	Beck & Tomann, "Chip Tester," IBM Technical Disclosure Bulletin, p. 4819 (January 1985).
E.P.K.	BN	Article by William Knauer entitled "Fixturing for Low-Current/Low Voltage Parametric Testing," appearing in Evaluation Engineering, (1990), pp. 150-153 <i>Nov.</i>
E.P.K.	BO	Hewlett-Packard, "Application Note 356-HP 4142B Modular DC Source/Monitor Practical Application," (Nov. 1987), pp. 1-4
E.P.K.	BP	Hewlett-Packard, H-P Model 4284A Precision LCR Meter, Operation Manual (December 1991) pp. 1-2, 6-9 and 6-15

EXAMINER <i>Ernest J. Kardes</i>	DATE CONSIDERED <i>1/09/05</i>
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.